

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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	C	US-6,358,759	03-2002	Hirabayashi, Yukiya	438/7
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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